

Notice of References Cited

Applicant/Patent PRATER et al.		Application/Control No. 08/871,029	
Examiner Daniel Larkin	Art Unit 2856	Page 1 of 1	

U.S. PATENT DOCUMENTS

	Document Number Country Code-Number-Kind Code	Date MM-YYYY ¹	Name	Classification ²	
A	5,172,002	12/1992	Marshall	250	306
B					
C					
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E					
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H					
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M					

FOREIGN PATENT DOCUMENTS

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N						
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NON-PATENT DOCUMENTS

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
U	Jung et al., "Novel Stationary-Sample Atomic Force Microscope With Beam-Tracking Lens", Electronic Letters, 04 February 1993, Vol. 29, No. 3, pp. 264-266.
V	
W	
X	

¹ A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a). ² Dates in MM-YYYY format are publication dates. ³ Classifications may be U.S. or foreign.